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| Notice of References Cited | Application/Control No. 10/726,028 | Applicant(s)/Patent Under Reexamination BUTLER, GLENN | |
| | Examiner Ahmed M. Farah | Art Unit 3735 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|--------------------|----------------|
| * | A | US-6,152,919 A | 11-2000 | Hakky, Said I. | 606/15 |
| * | B | US-5,026,367 | 06-1991 | Leckrone et al. | 606/7 |
| * | C | US-5,041,108 | 08-1991 | Fox et al. | 606/7 |
| * | D | US-5,651,783 | 07-1997 | Reynard, Michael | 606/4 |
| * | E | US-6,605,082 B2 | 08-2003 | Hareyama et al. | 606/11 |
| * | F | US-5,902,328 A | 05-1999 | LaFontaine et al. | 607/116 |
| * | G | US-5,466,234 A | 11-1995 | Loeb et al. | 606/15 |
| * | H | US-5,573,531 A | 11-1996 | Gregory, Kenton W. | 606/14 |
| * | I | US-6,203,542 B1 | 03-2001 | Ellsberry et al. | 606/41 |
| * | J | US-2003/0159700 A1 | 08-2003 | Laufer et al. | 128/898 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

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